

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/618,944	CHEN, CHIH-WEI	
Examiner		Art Unit		Page 1 of 1
Andrew Setlak		2166		

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,822,581 A	10-1998	Christeson, Orville	713/1
*	B	US-2002/0099974 A1	07-2002	Lin, Hou-Yuan	714/13
*	C	US-6,459,624 B1	10-2002	Kuo, Yao-Jung	365/185.33
*	D	US-6,754,767 B2	06-2004	Gold, Stephen	711/114
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP 09330272 A	12-1997	Japan	NAKARAI, KENICHI	
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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